Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (DTMOS)

# **TK40J60T**

### **Switching Regulator Applications**

• Low drain-source ON resistance: RDS (ON) =  $0.068 \Omega$  (typ.)

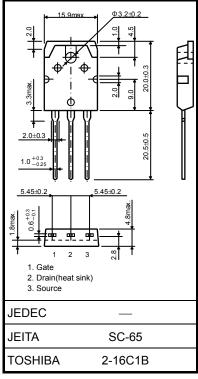
• High forward transfer admittance:  $|Y_{fs}| = 25 \text{ S (typ.)}$ 

• Low leakage current:  $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 600 \, V)$ 

• Enhancement-mode:  $V_{th} = 3.0 \sim 5.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	600	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	40		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	80	Α	
Drain power dissipati	on (Tc = 25°C)	PD	400	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	576	mJ	
Avalanche current (Note 3)		I <sub>AR</sub>	40	Α	
Repetitive avalanche energy		E <sub>AR</sub>	40	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

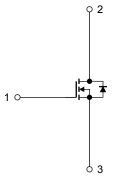
Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	0.313	°C/W	
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W	

Note 1: Please use devices on conditions that the channel temperature is below 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25 °C (initial), L = 0.63 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 40 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.



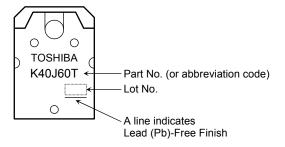
# Electrical Characteristics (Ta = 25°C)

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±1	μА
Drain cut-off current		I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	600	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	3.0	_	5.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		0.068	0.08	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 20 A	6	25	_	S
Input capacitance		C <sub>iss</sub>		_	3900	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	280	_	pF
Output capacitance		Coss		_	9200	_	
Switching time	Rise time	t <sub>r</sub>	$\begin{array}{c c} 10 \text{ V} & \text{I}_D = 20 \text{A} & \text{V}_{OUT} \\ \hline \text{VGS} & \text{V} & \text{RL} = \\ \hline 0 & \text{V} & \text{NDD} \approx 300 \text{ V} \\ \\ \hline \text{Duty} \leq 1\%, \ t_W = 10 \ \mu\text{s} \end{array}$	—	60	—	. ns
	Turn-on time	t <sub>on</sub>		_	120	—	
	Fall time	t <sub>f</sub>			15		
	Turn-off time	t <sub>off</sub>		_	200	_	
Total gate charge		Qg		_	67	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 40 \text{ A}$	_	45	_	nC
Gate-drain charge		Q <sub>gd</sub>			22		

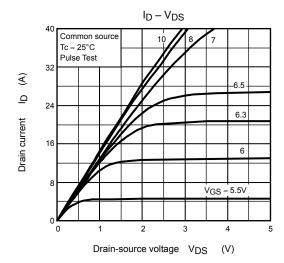
# Source-Drain Ratings and Characteristics (Ta = 25°C)

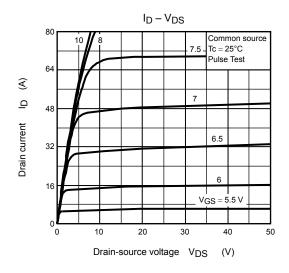
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	40	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	80	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 40 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 40 A, V <sub>GS</sub> = 0 V,	_	550	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	14	_	μС

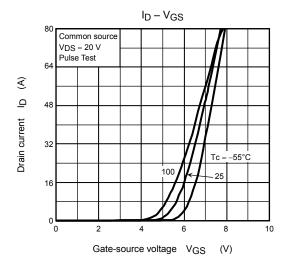
# Marking

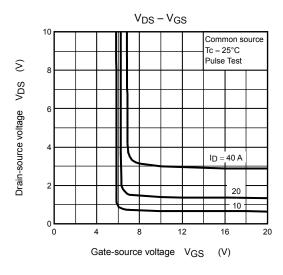


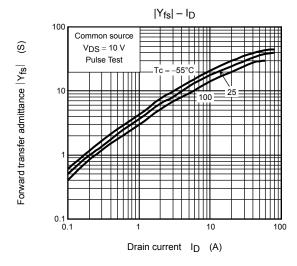
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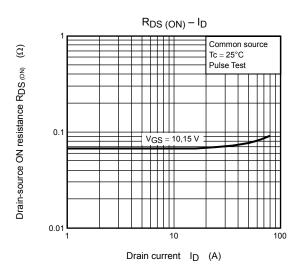




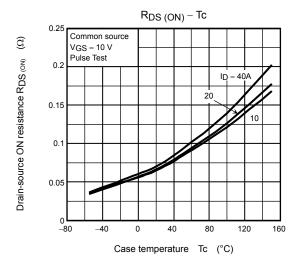


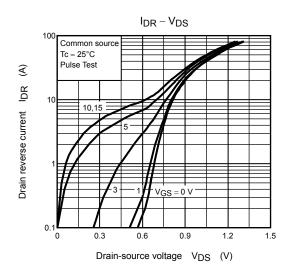


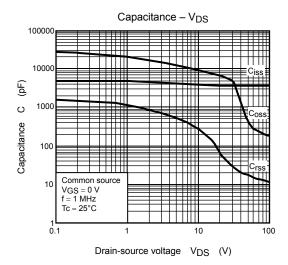


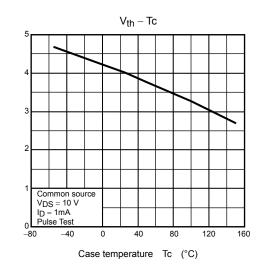


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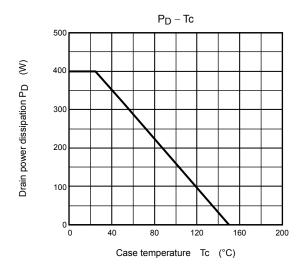


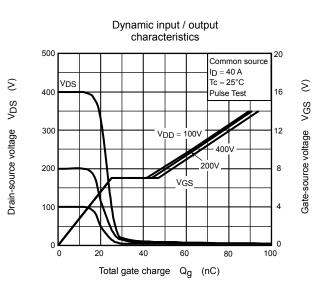


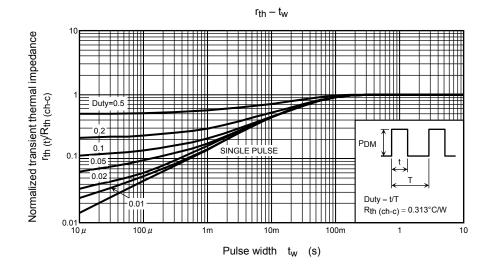
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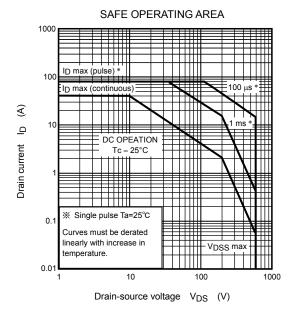
Gate threshold voltage Vth

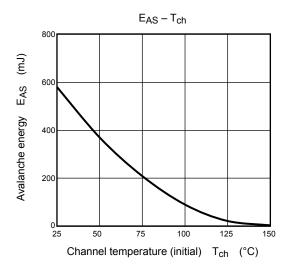
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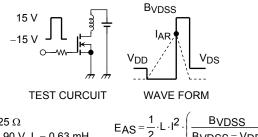












$$R_G = 25 \Omega$$
  
 $V_{DD} = 90 \text{ V, L} = 0.63 \text{ mH}$   $E_{AS} = \frac{1}{2} \cdot \text{L} \cdot \text{I}^2 \cdot \left(\frac{\text{BVDSS}}{\text{BVDSS} - \text{V}_{DD}}\right)$ 

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20070701-EN GENERAL

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